

## PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1  
 Stylesheet Version v1.2

EPAS ID: PAT6282779

<b>SUBMISSION TYPE:</b>	NEW ASSIGNMENT	
<b>NATURE OF CONVEYANCE:</b>	ASSIGNMENT	
<b>CONVEYING PARTY DATA</b>		
	<b>Name</b>	<b>Execution Date</b>
	CARL ZEISS SMT GMBH	08/12/2020
<b>RECEIVING PARTY DATA</b>		
<b>Name:</b>	LEYBOLD GMBH	
<b>Street Address:</b>	BONNER STR. 498	
<b>City:</b>	KOLN	
<b>State/Country:</b>	GERMANY	
<b>Postal Code:</b>	50968	
<b>PROPERTY NUMBERS Total: 6</b>		
<b>Property Type</b>	<b>Number</b>	
<b>Application Number:</b>	15244720	
<b>Patent Number:</b>	9035245	
<b>Patent Number:</b>	10304672	
<b>Patent Number:</b>	10236169	
<b>Patent Number:</b>	10141174	
<b>Application Number:</b>	16687236	
<b>CORRESPONDENCE DATA</b>		
<b>Fax Number:</b>	(612)334-3312	
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>		
<b>Phone:</b>	6123343222	
<b>Email:</b>	cnelson@wck.com	
<b>Correspondent Name:</b>	THEODORE M. MAGEE	
<b>Address Line 1:</b>	121 SOUTH EIGHTH STREET, SUITE 1100	
<b>Address Line 4:</b>	MINNEAPOLIS, MINNESOTA 55402	
<b>ATTORNEY DOCKET NUMBER:</b>	L209.0000G01	
<b>NAME OF SUBMITTER:</b>	THEODORE M MAGEE	
<b>SIGNATURE:</b>	/Theodore M. Magee #39758/	
<b>DATE SIGNED:</b>	09/03/2020	
<b>Total Attachments: 4</b>		

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## ASSIGNMENT CONFIRMATION OF PATENTS AND PATENT APPLICATIONS

**WHEREAS**, Carl Zeiss SMT GmbH, Rudolf-Eber-Straße 2, 73447 Oberkochen, Germany ("ZEISS"), is the owner of record of the Assigned Patents (as defined below);

**WHEREAS**, Leybold GmbH, Bonner Str. 498, 50968 Köln, Germany ("**Purchaser**"), is desirous of acquiring the entire interest in and to the Assigned Patents (as defined below);

**WHEREAS**, ZEISS and Purchaser have entered into an Asset Purchase Agreement for certain patents and patent applications dated DD.MM.YYYY ("**Asset Purchase Agreement**") wherein ZEISS has agreed to sell and Purchaser has agreed to purchase the Assigned Patents, subject to all Encumbrances (as defined below);

**WHEREAS**, Purchaser has agreed to grant a non-exclusive on demand back license to Seller's Licensees as set forth in **Section 1.08. f)** of the Asset Purchase Agreement thereof as a condition of and as part of the consideration for the Parties entering into the Asset Purchase Agreement;

**WHEREAS**, for the purpose of this Assignment, the following terms, whether in singular or in plural form, when used with a capital initial letter shall have the respective meanings as follows:

"**Affiliate**" any legal entity that directly or indirectly controls a Person (hereinafter "**Parent Company**"), or is controlled by a Person or its Parent Company. "**Control**" means direct or indirect ownership of more than fifty per cent (50%) of the stock of such entity, or more than a fifty per cent (50%) interest, direct or indirect, in the decision-making authority of such entity.

"**Assigned Patents**" means the issued patents and patent applications listed in Appendix A of this Assignment.

"**Encumbrances**" means any commitments, licenses, immunities, releases or other rights relating to any of the Licensed Patents, whether express, implied or otherwise, that are made, entered into or granted by, or that arise from any actions taken by ZEISS or any current or former Affiliate of ZEISS on or before the Closing Date.

"**Licensed Patents**" means the Assigned Patents; and (a) all extensions, renewals, reissues, and reexaminations of the issued patents of the Assigned Patents and (b) all applications claiming any right of priority to or through the patent applications of the Assigned Patents (and all patents issuing on such applications), filed or applied for by Purchaser, by any of Purchaser's Affiliates or by any subsequent successors to, or assigns of, any of the same in any country after the Closing Date.

"**Person**" means any natural person, corporation, company, partnership, association, sole proprietorship, trust, joint venture, non-profit entity, institute, Governmental Entity, trust association or other form of entity not specifically listed herein including, without limitation, ZEISS or any of its Affiliates, or Purchaser or any of its Affiliates.

**NOW, THEREFORE**, to all whom it may concern, be it known that for good and valuable consideration to ZEISS in hand paid, the receipt of which is hereby acknowledged, ZEISS has sold, assigned, transferred, and set over onto Purchaser, subject to all Encumbrances, its entire right, title, and interest in and to all of the Assigned Patents, for Purchaser's own use and for the use of its assigns, successors, and legal representatives, to the full end of the term of each of the Assigned Patents, including: (i) all past, present, and future causes of action, enforcement rights and claims to pursue past, present and future damages derived by reason of patent infringement thereof (to the extent such damages are not already paid, awarded or contractually owed to ZEISS, its Affiliates or any

predecessor of ZEISS or ZEISS's Affiliates) and to seek injunctive relief and other remedies at law or in equity; (ii) the right to file for extensions, renewals, reissues and reexaminations of the issued patents of the Assigned Patents; and (iii) the right to file for applications claiming any right of priority to or through the patent applications of the Assigned Patents (and obtain ownership of all patents issuing on such applications), filed or applied for by Purchaser or by any of Purchaser's Affiliates. For clarity, the foregoing assignment does not include (i) any trademarks, trade dress, trade names, or other indicia of origin; (ii) except for inventions of the Assigned Patents, any inventions or discoveries, whether patentable or not, and registrations, invention disclosures, patents and applications therefor; (iii) any trade secrets, confidential information or know-how; (iv) any works of authorship, whether copyrightable or not; and (v) any other intellectual property or proprietary rights of ZEISS, its Affiliates or any predecessor of ZEISS or ZEISS's Affiliates.

**IN TESTIMONY WHEREOF**, ZEISS by its fully authorized representatives has executed this Assignment as of the dates indicated below.

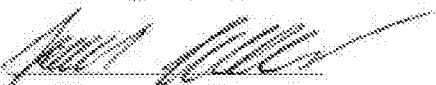
Carl Zeiss SMT GmbH

Leybold GmbH

Oberkochen, 12 August 2020

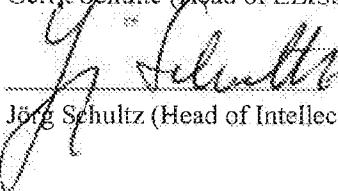
Burgess Hill, 24 August 2020  
United Kingdom

**Carl Zeiss SMT GmbH**

  
Gerrit Schulte (Head of ZEISS Ventures)

  
KATE C RAWLINS

HEAD OF INTELLECTUAL PROPERTY

  
Jörg Schultz (Head of Intellectual Property – Prosecution and Legal)

A	B	C	D	E	F	G	H	I	J
Device Family Number	Status	Application Date	Apparatus Number	Publication Date	Publication Number	Date of Grant	Patent Number	Priority	
Patent Family: P19567 Title: Method for mass spectrometric examination of gas mixtures and mass spectrometer therefor									
P1956700	Filed	30.03.2013	US10363204	08.06.2018	US10363204	08.06.2018			
P1956701	Filed	27.03.2014	EP2072606	08.06.2018	EP2072606A2		DE 10.01.2013	102013201499.6	
P1956710	Granted	28.03.2014	EP2094903	16.03.2015	101285138P23A	23.03.2019	US 30.01.2013	61/759309	
P1956703	Filed	27.03.2014	US10363204	08.06.2018	US2016372310A1		US 30.01.2013	102013201499.6	
P1956700P1	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P2	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P3	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P4	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P5	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P6	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P7	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P8	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P9	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P10	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P11	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P12	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P13	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P14	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P15	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P16	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P17	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P18	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P19	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P20	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P21	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P22	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P23	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P24	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019	US 30.01.2013	61/759309	
P1956700P25	Granted	27.03.2014	EP2084765	09.12.2015	EP2951951A2	23.10.2019			

33	Patent Family: P21155; Title: Ionization device with mass spectrometer thereon								
34	P21155A1	Filed	03.12.2015	JP20150010494	09.05.2019	JP2015013391A2		DE 10 12 2014	102015000000.0
35	P21162TW	Granted	13.12.2015	TW2015019115B	16.07.2016	TW2015026435A	21.06.2017	TW2015000079	DE 10 12 2014
36	P21163WOEN	Granted	03.12.2015	CI20150005863B	01.08.2017	CH107004551A	25.09.2018	CH107004551B	DE 10 12 2014
37	P21163WOEPCH	Granted	03.12.2015	EP20150804140	25.10.2017	EP3234978A1	26.09.2018	EP3234978B1	DE 10 12 2014
38	P21163WOEPDE	Granted	03.12.2015	EP20150804140	25.10.2017	EP3234978A1	26.09.2018	EP3234978B1	DE 10 12 2014
39	P21163WOEPFR	Granted	03.12.2015	EP20150804140	25.10.2017	EP3234978A1	26.09.2018	EP3234978B1	DE 10 12 2014
40	P21163WOEPNL	Granted	03.12.2015	EP20150804140	25.10.2017	EP3234978A1	26.09.2018	EP3234978B1	DE 10 12 2014
41	P21163WOJP	Granted	03.12.2015	JP20150537665T	11.03.2016	JP20150537665T	06.02.2016	JP20150537665T	DE 10 12 2014
42	P21163WOKR	Granted	03.12.2015	KR2015013791	29.08.2017	KR2015013791	02.07.2017	KR2015013791	DE 10 12 2014
43	P21163WOUS	Granted	03.12.2015	US20152661783	06.09.2017	US20152661783	19.03.2018	US20152661783	DE 10 12 2014
44	Patent Family: P21541; Title: Method for sampling a gas by mass spectrometry and mass spectrometer								
45	P21541DE	Filed	04.05.2015	DE2015201180	24.11.2016	DE 102015201180 A1			
46	P21541JP	Filed	17.05.2016	JP2016119144					DE 04.05.2015
47	P21541KR	Filed	17.05.2016	JP2016119145					DE 04.05.2015
48	P21541WOEP	Filed	17.05.2016	EP20150537665T	14.03.2016	EP 3205501 A1			DE 04.05.2015
49	P21541WOJP	Filed	17.05.2016	JP20170357937T	05.07.2018	JP 20160188019			DE 04.05.2015
50	P21541WOUS	Granted	17.05.2016	US20170795405	08.02.2018	US 20160000002 A1	22.01.2018	US10141174B	DE 04.05.2015
51	Patent Family: P22215; Title: Apparatus and method for detecting ions								
52	P22215DE	Filed	10.05.2016	KR20160000000	10.11.2017	DE 1020160000000			
53	P22215TW	Filed	06.05.2017	TW20170115119	16.02.2018	TW2017005086A			DE 10.05.2016
54	P22215WOEP	Filed	26.04.2017	EP20170158000	20.03.2018	EP20170158000			DE 10.05.2016
55	Patent Family: P22794; Title: METHOD FOR ANALYZING A GAS BY MASS SPECTROMETRY, AND MASS SPECTROMETER								
56	P22794DE	Filed	29.05.2017	DE20171030000	20.11.2018	DE 1020171030000			
57	P22794WO	Filed	02.05.2018	WO2018011108	06.12.2018	WO2018011108			
58	P22794WOUS	Filed	02.05.2018	10201700996.2					DE 29.05.2017
59	Patent Family: P23834; Title: Method for real-time monitoring of a process and mass spectrometer								
60	P23834TW	Filed	08.01.2018	137100651	01.09.2019	TW201802263A			WO 21.02.2017
61	P23834WOEP	Filed	21.02.2017	EP20170706728	01.01.2020	EP20170706728			PCT/EP2017/000004
62	P23834WOKR	Filed	21.02.2017	KR20190272284	21.10.2019	KR20190119106A			
63	Patent Family: P23880; Title: Pressure detection								
64	P23880DE	Filed	02.04.2018	1020180000000					
65	P23880TW	Filed	11.05.2018	PCT/EP2018/000000	25.03.2020	EP20180000000			DE 02.04.2018
66	P23880WO	Filed	05.05.2018	WO20180000000	20.03.2020	PCT/EP2018/000000			DE 02.04.2018
67	Patent Family: P23780; Title: Gas probe								
68	P23780DE	Filed	27.08.2018	DE1020182000000					
69	P23780WO	Filed	12.08.2018	PCT/EP2018/015277					DE 27.08.2018
70	Patent Family: P26372; Title: Ion Trap								
71	P26372DE	Filed	01.10.2019	DE102019232400.0					
72	Patent Family: P26373; Title: High Pressure Source								
73	P26373DE	Filed	06.06.2019	DE20190200278	01.08.2019	DE 1020190200278			
74	P26373WO	Filed	11.05.2020	PCT/EP2020/053070					DE 06.06.2019
75	P26373TW	Filed	05.06.2020	TW2020118935					DE 06.06.2019
76	Patent Family: P26416; Title: Pressure controlled stage								
77	P26416DE	Filed	07.10.2019	DE102019232400.0					
78	Patent Family: P26504; Title: Mass spectrometer								
79	P26504WO	Filed	22.10.2019	PCT/EP2019/078764					
80	Patent Family: P26754; Title: Mass spectrometer								
81	P26754DE	Filed	18.13.2020	DE102020130091.7					
82	Patent Family: P27225; Title: Verfahren zur Detektion von geladenen Teilchen								
83	P27225DE	Filed	11.03.2020						
84									